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Title: Neutron Reflectometry for the Study of Thin-Film Ionomers

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Neutron Reflectometry for the Study of Thin-Film Ionomers

Effect of Substrate and Cation Exchange on Ionomer Structure

Derek Richard
Los Alamos National Lab



Personal Background

A little about me:

- Attended the University of Arkansas for bachelor in chemical engineering
- Internship at Cross Oil Refinery South Arkansas
- Research under Dr. Lauren Greenlee
 - Reclamation of phosphorus from waste water by electrochemistry
 - Microelecrode, split and single cell.
- WERC design competition
 - Novel process for removal of gypsum from mine waste water
- Los Alamos National Laboratory, Materials Physics and Applications group (MPA-11)









LANL

Los Alamos National Lab

U.S. Department of Energy

36 square miles of DOE-owned property

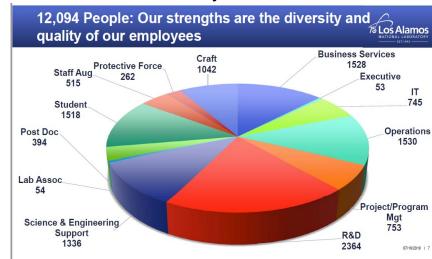
More than 2,000 individual facilities, including 47 technical areas with 8 million square feet under roof including



Los Alamos is located in the South-Western U.S., in the mountains in Northern New Mexico at 7500 ft. elevation (2300 meters)



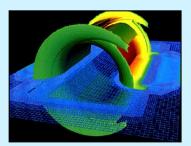
Picture overlooking the main technical area of Los Alamos, from the Pajarito Ski Area



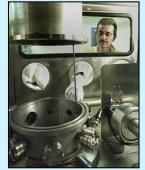


LANL Mission: National Security

Stockpile Stewardship



Large-Scale Simulation Stockpile Stewardship



Pit Manufacturing



B61-7/11 Strategic Bomb

Proton radiography





W76, W78, W88 for Trident & Minuteman III

Global Security



Non Proliferation





Intelligence Analysis



Space Systems Six other product lines

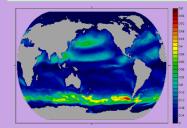
Energy Security



Materials and Concepts for Clean Energy



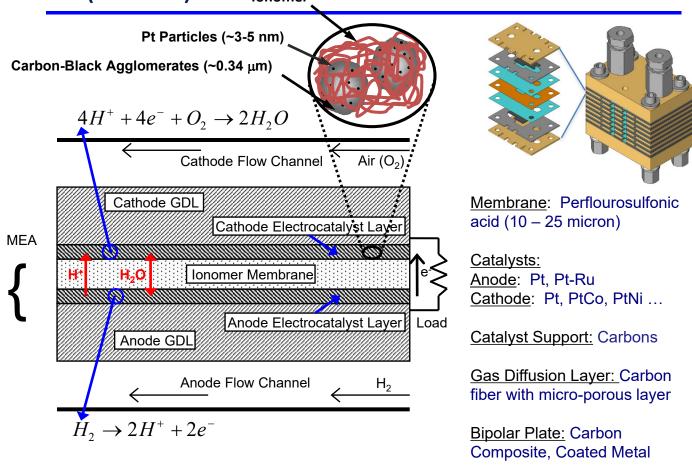
Nuclear Energy



Climate Energy Nexus



Components: Polymer Electrolyte Membrane Fuel Cell (PEMFC)







FC-PAD: Consortium to Advance Fuel Cell Performance and Durability



Energy Efficiency & Renewable Energy

Fuel Cell Technologies Office (FCTO)

Approach

Couple national lab capabilities with funding opportunity announcements (FOAs) for an influx of innovative ideas and research

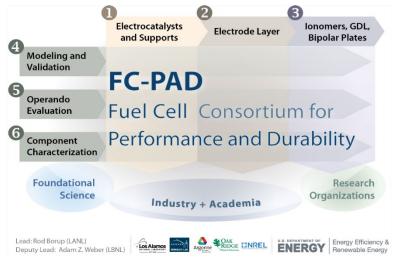
Objectives

- · Improve component stability and durability
- Improve cell performance with optimized transport
- Develop new diagnostics, characterization tools, and models

Consortium fosters sustained capabilities and collaborations



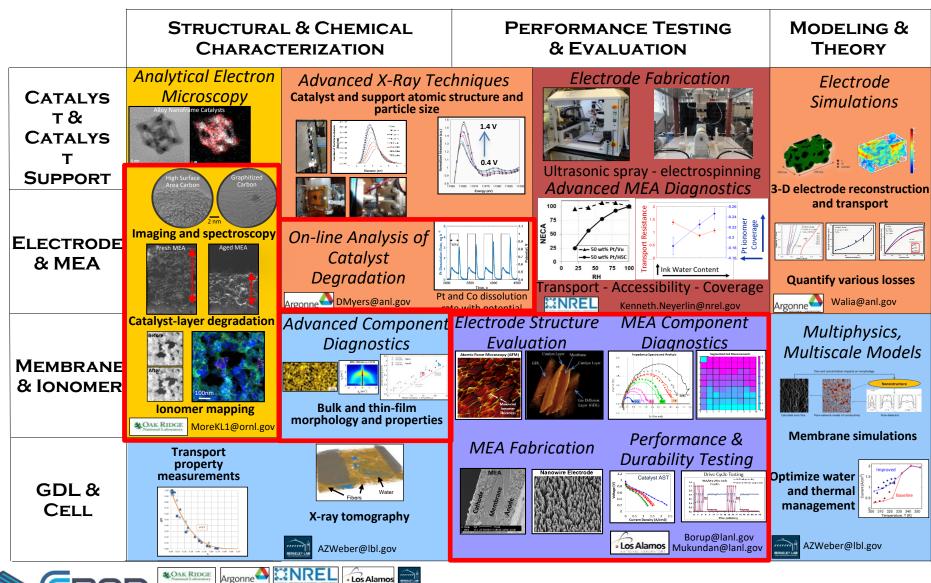
Structured across six component and cross-cutting thrusts







FC-PAD NL Capabilities





Fuel Cell Testing

Test stations

- Used to measure the performance of operating fuel cells
- Fully controllable conditions (humidity, temperature, flow rates, pressures, load)
- Programmable run cycles and data collection (Break-in, pole curves, impedance, crossover, accelerated aging, etc.)



Fuel Cell Technologies Test Station



Bio-logic Potentiostat

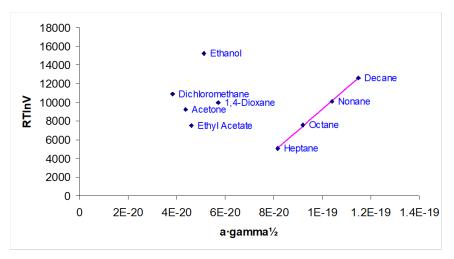
Potentiostat

- Used in tandem with a test station to measure electrochemical performance of fuel cells
- Catalyst activity, accelerated aging, test for cross membrane shortages, etc.

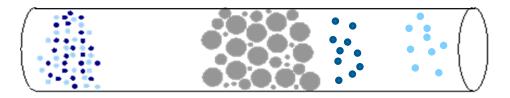


IGC: Inverse Gas Chromatography

- Sample is stationary, probe is mobile
- Column packed with sample
- Gases of known properties are used to probe the sample



Analytical Gas Chromatography



INVERSE Gas Chromatography

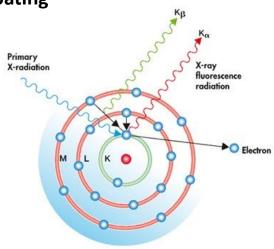


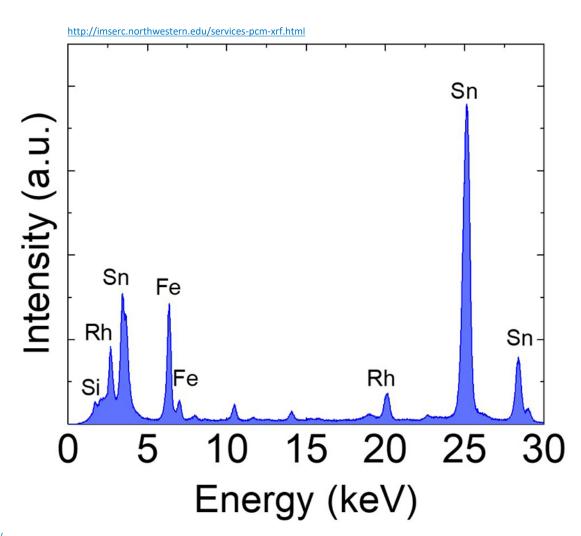
- Can measure various properties
- Primarily used for surface energy
- Surface wettability



XRF: X-Ray Fluorescence

- Uses X-Rays to determine presence of heavier elements
- Can determine concentration of compounds over a given sample area
- Typically used to measure Pt loading on Catalyst layers
- can also be used to determine thickness of thinfilm metals on Si wafers from sputter coating





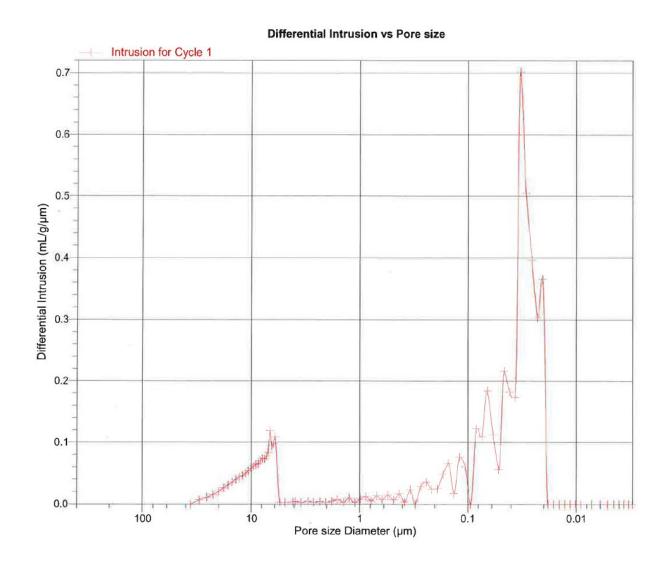
https://wpo-altertechnology.com/xrf-x-ray-fluorescence-spectroscopy-hi-rel-parts/



MIP: Mercury Intrusion Porosimetry

Measure
 mercury
 intrusion at
 increasing
 pressure to
 measure pore
 size and
 distribution

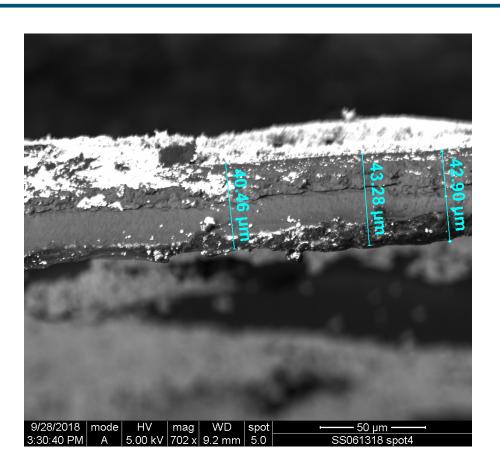
 Useful for characterization of gas diffusion and catalyst layers





SEM (Scanning Electron Microscopy)

- Micro scale imaging
- Cross sections of MEAS for determination of aging affects
- Elemental distribution (looking for contamination, catalyst distribution)
- Microscale- nanoscale morphology



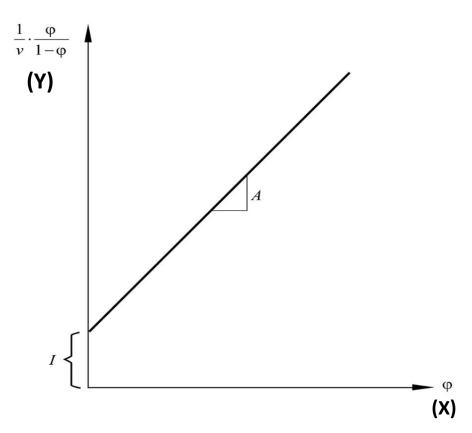
BET (Brunauer-Emmett-Teller) Surface Area

- Method for measuring specific surface area of solid surfaces
- Extension of Langmuir theory (monolayer molecular adsorption) to multilayer adsorption
- Gas diffusion layer, catalyst layer



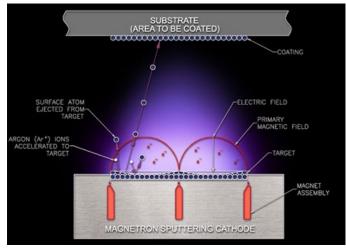
$$rac{1}{v\left[(p_0/p)-1
ight]} = rac{c-1}{v_{
m m}c}\left(rac{p}{p_0}
ight) + rac{1}{v_mc},$$

$$\mathbf{Y} = \mathbf{A} * (\mathbf{X}) + \mathbf{I}$$

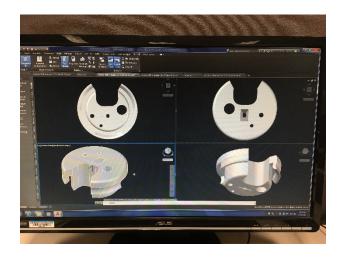


Other Techniques

- Profilometry
 - Laser and stylus
- Spin Coating
- PVD (Physical Vapor Deposition) thin film sputter coating
- XRD (X-Ray Diffraction)
- XRR (X-Ray Reflectometry)
- 3D modeling with AutoCAD and eMachineShop



https://nptel.ac.in/courses/115103039/module16/lec39/4.html

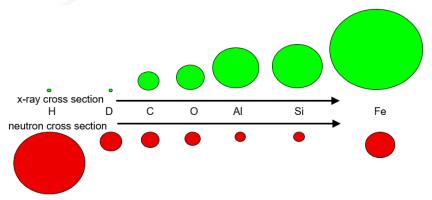


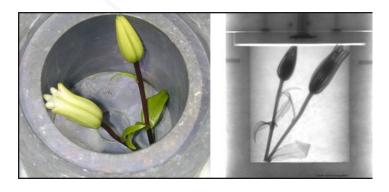


Neutron Imaging at NIST

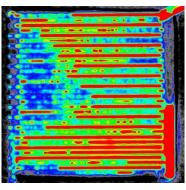
Measuring Fuel Cell Water Management

Neutrons are an excellent probe for hydrogen in metal since metals have a much smaller cross section to thermal neutrons than hydrogen does.





In-plane water distribution



Beer-Lambert law

$$I = I_0 e^{-\mu t}$$

 I_0 = reference (dry) image

I =attenuated (wet) image

 μ = attenuation coefficient of water

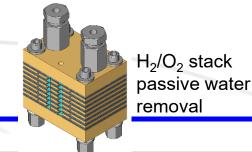
t =liquid water thickness

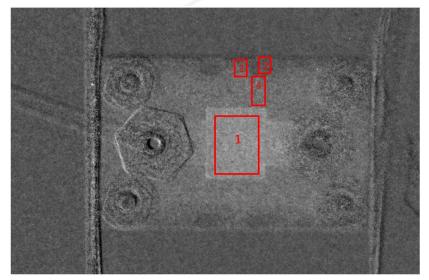
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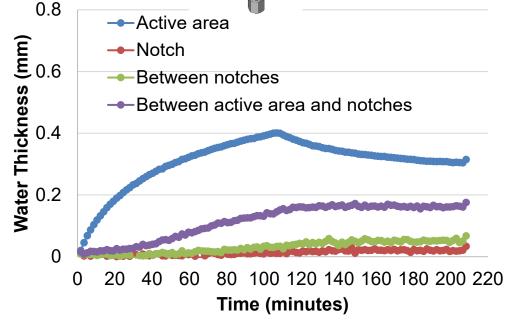




Water content profiles 2b stack: 400 µm membrane stack (25C)







- wetting at 3 mA followed by subsequent natural dissipation.
 - Monitoring water concentration during wetting/drying procedures
 - Indicates water is removed (as designed) from active area by diffusion to exposed membrane at designed notches

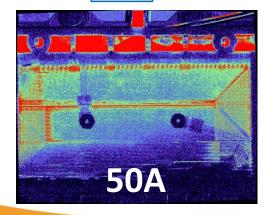




Commercial State-of-Art: Toyota Mirai

- 5 cell- 255 cm² active area per cell
- Stack from USCAR (Ford)
- Aged cells from USCAR (GM)

Top Edge Of Stack 7 Ox Outlets Anode Plate Coolant Surface Air Inlets



Neutron Image (H₂O) of operating stack



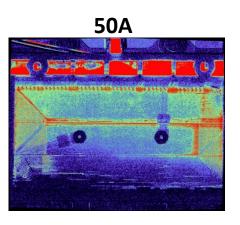
FC-PAD (LANL led Consortium) conducted full materials and performance analysis of Toyota Mirai fuel cell to set new benchmark for materials

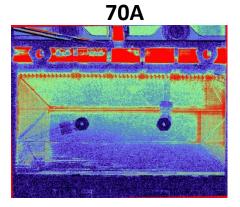


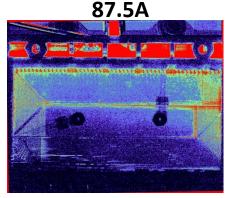


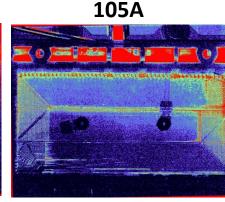


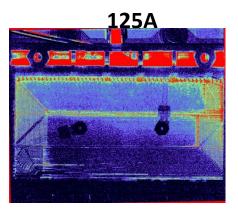
USCAR Matrix of Operating Conditions

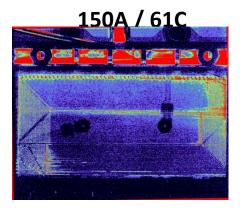


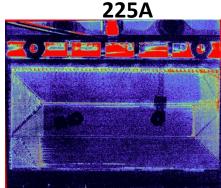


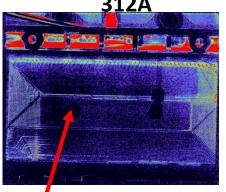












Notes: Unstable at *12.5 Amps* 450 Amp point insufficient H2

High Current & Flowrates show much less liquid water than low current/flowrates



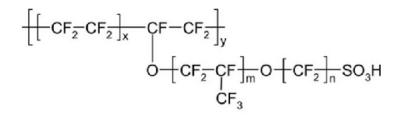


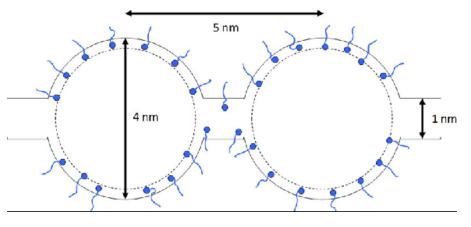
What is Nafion: fuel cell electroyte



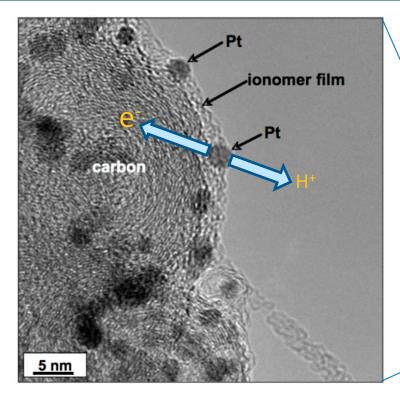
http://www.nafionstore.com/

- Polyflourosulfonic Acid
- PTFE backbone (Hydrophobic)
- Sulfonic acid side chain (Hydrophilic)
- Creates water channels that conduct protons
- Does not conduct electrons
- Used as the electrolyte membrane and ionomer in PEM fuel cells
- Bulk behavior is well characterized
- Thin film regimes (ionomer) function differently and are not well characterized



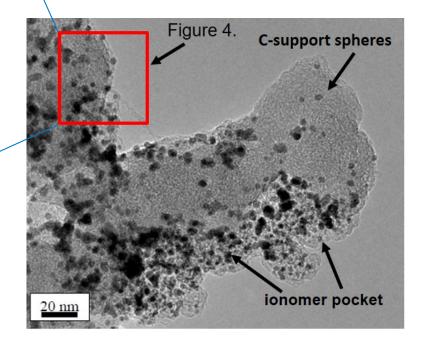


Why Look at Thin Film Ionomer?



- Ce used as radical scavenger
- Co leaches from Pt/Co catalyst

- Thin ionomer layer coats carbon and Pt and is responsible for proton transport
- Affects mass transport properties (oxygen diffusion)





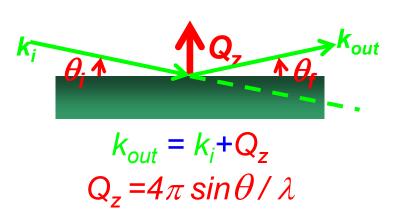
Karren More, Rod Borup and Kimberly Reeves ECS Trans. 3(1), 717 (2006)

What is Neutron Reflectometry?

Technique used to investigate thin-film profiles for internal structure changes

<u>Advantages</u>

- Provides density, layering, roughness, and composition information
- Angstrom level resolution
- Effectively non-destructive
- Good resolution for low-Z elements
- Isotope sensitive (H vs. D)
- Neutrons are highly penetrative



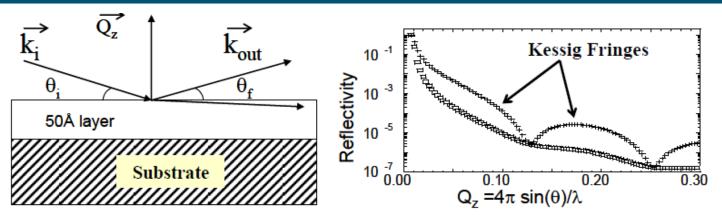
Limitations

- Only provides information along vertical axis (z)
- Excessive layering can be difficult to conclusively model
- Needs large, atomically smooth surface

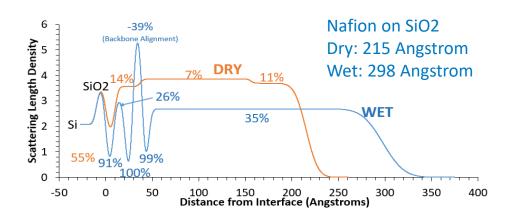


~4 locations in U.S.: LANSCE, SNS, NIST, HFIR

NR Basics



Schematic of single-layer NR experiment showing basic principles (left) and reflectivity profiles for a bare substrate and film/substrate system (right); reflectivity is dimensionless and Qz has units of Å-1.



Assuming dense Nafion SLD (Scattering Length Density) is 4.15 and knowing H2O SLD is -0.56

- Swelling
- H2O content



Sample Prep

Silicon wafer Substrate

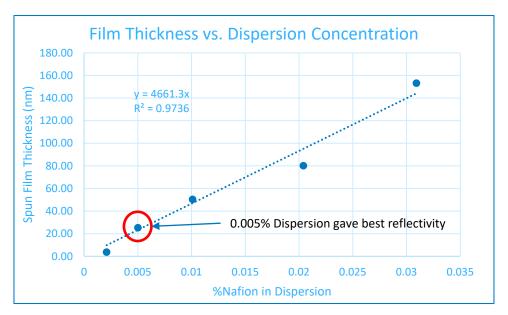
- UV-Ozone cleaned
- Native oxide layer
- Sputter coated platinum
- Sputter coated carbon

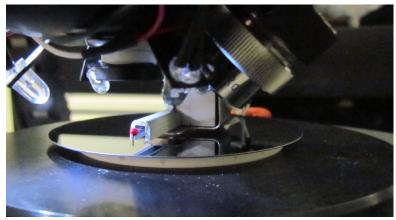
Coating Process

- Spin coated nafion/IPA Dispersion
- 3500 RPM 60 sec
- Annealed at 150C, 1hr

Doping Process

- Submersion in water with appropriate dopant
- Water bubble with appropriate dopant
- Dried at 50C
- Dependent on adhesion

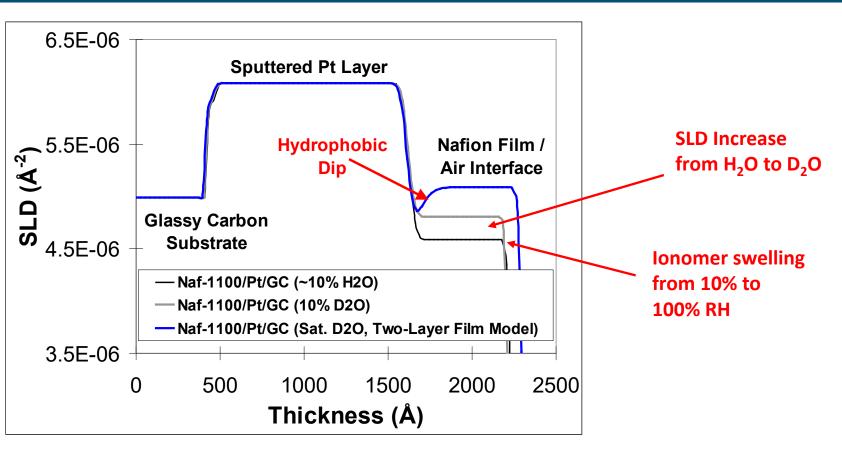




Checking wafer surface roughness with profilometer



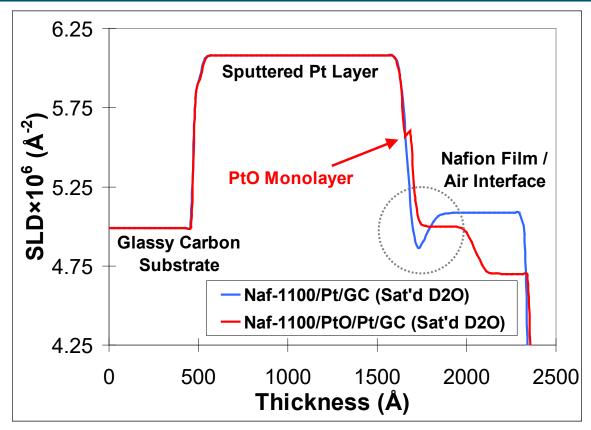
NR SLD profiles for Nafion® 1100/Pt bilayer system on GC substrate



Dip in SLD at Pt/Nafion interface for saturated D₂O indicates hydrophobic surface



Nafion Structure comparison on Pt versus PtO



Nafion interface / water content rearranges with hydrophobic Pt versus hydrophillic Pt surface

- Dip in SLD at Pt/Nafion interface for saturated D₂O indicates hydrophobic surface
- No SLD dip present for PtO
 → PtO hydrophilic surface
- As side chain density increases, structure is more complicated
- Water concentrations increase near Pt substrate surface (hydrophilic)
- Nafion interface and/or water content rearranges with hydrophobic Pt versus hydrophillic Pt surface





Current NR Work

Erik Watkins (LANSCE): Neutron Reflectometry (ASTERIX) Derek Richard: Neutron Reflectometry, sample prep, and modeling

Substrates

- SiO2
- Pt (on Ti/SiO₂/Si)

Environments

- Dry
- •H₂O
- •D₂O

<u>Ionomer</u>

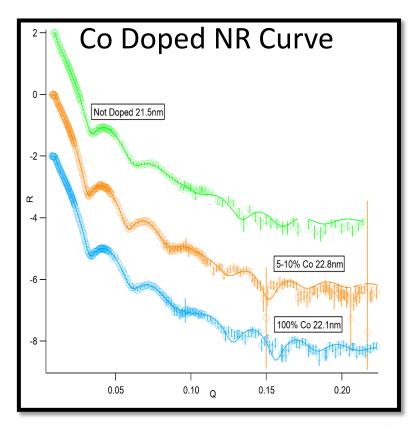
 Nafion (~20-30nm dry thickness)

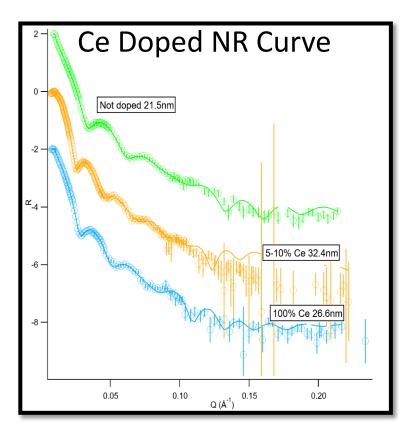
Dopant

- 5-10% Ce
- 100% Ce
- 5-10% Co
- 100% Co



Effect of Co and Ce Exchange on Structure of Dry Nafion SiO2/Si Substrate



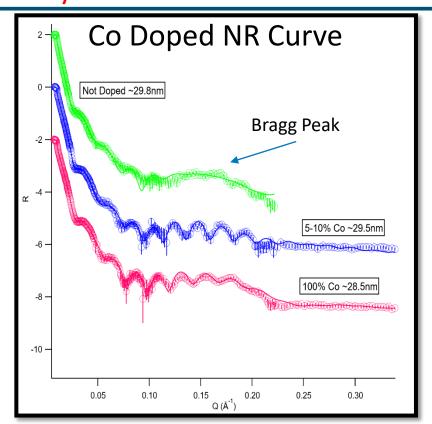


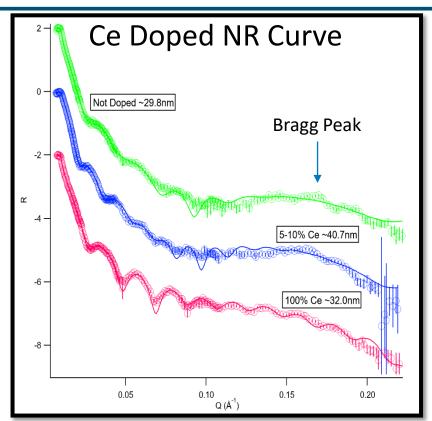
No Bragg peaks on SiO2/Si substrate when dry

- Modeling indicates nearly identical structure
- No obvious layering structure



Effect of Co and Ce Exchange on Structure of Hydrated Nafion SiO2/Si Substrate



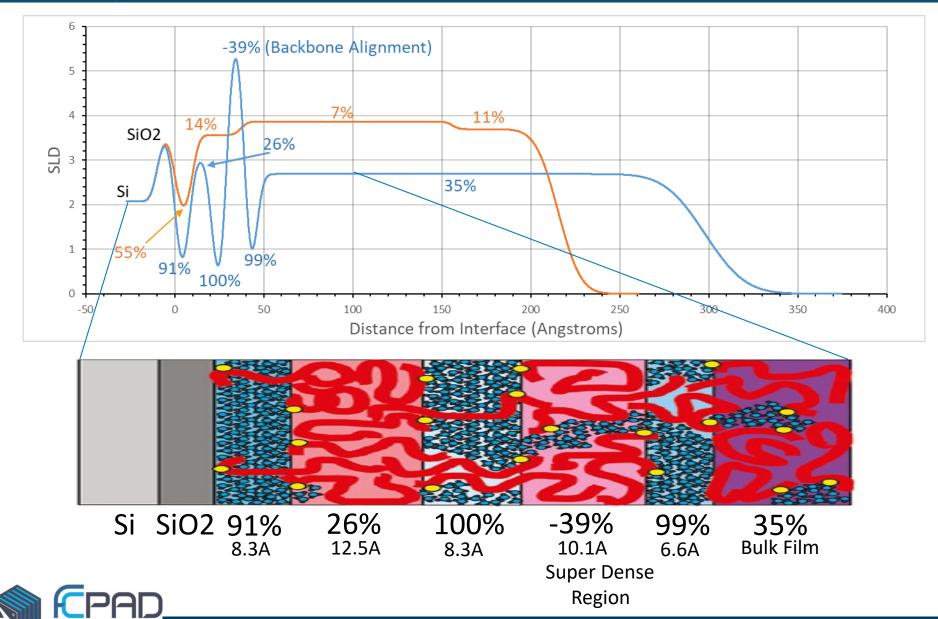


Bragg peak indicates repeated layering structure on SiO₂/Si substrate

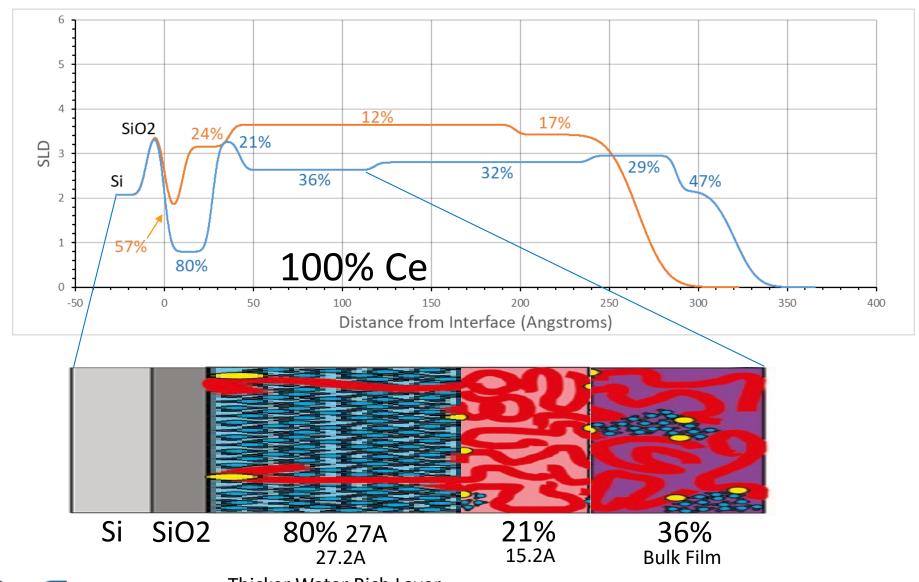
- Consistent with previous studies
- Dopants appear to affect layering structure
- Model: build structure by varying layer thicknesses, and SLD, then back-calculate theoretical curve and minimize variance

Undoped Film Structure (Hydrated)

8 – layer model



Doped Film Structure (Hydrated)



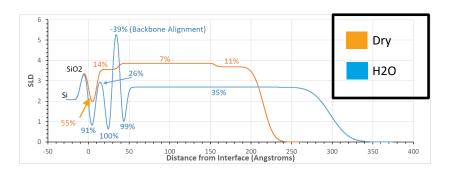


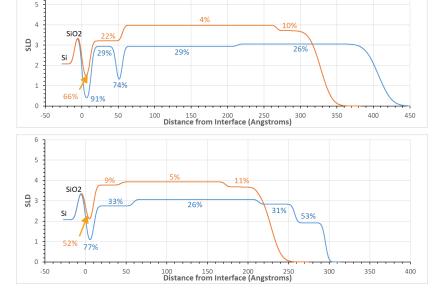
Thicker Water Rich Layer

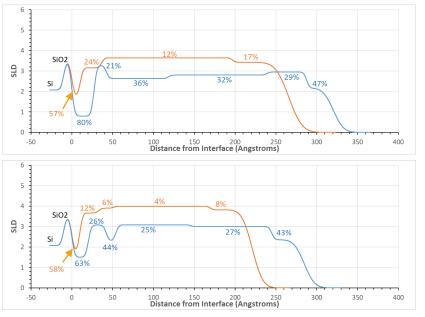
%Water Content by Layer

SiO2/Si Substrate

- Nearly identical structure under dry conditions
- Dopants disrupt interface structure observed in undoped films
- Super dense Nafion only observed in undoped film
- 100% exchanged films have larger low SLD layers at interface (higher interface water content)

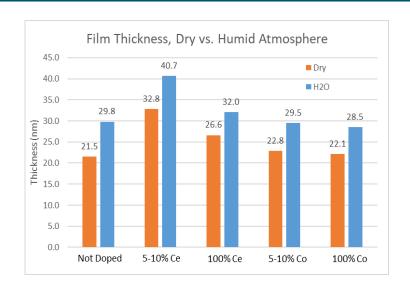


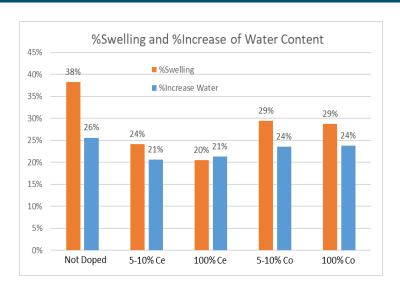


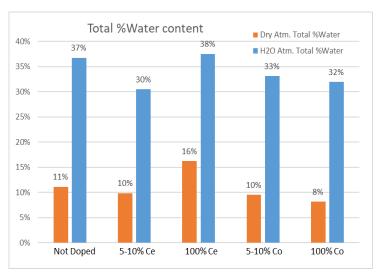




Effect of Dopant on Water Uptake and Swelling



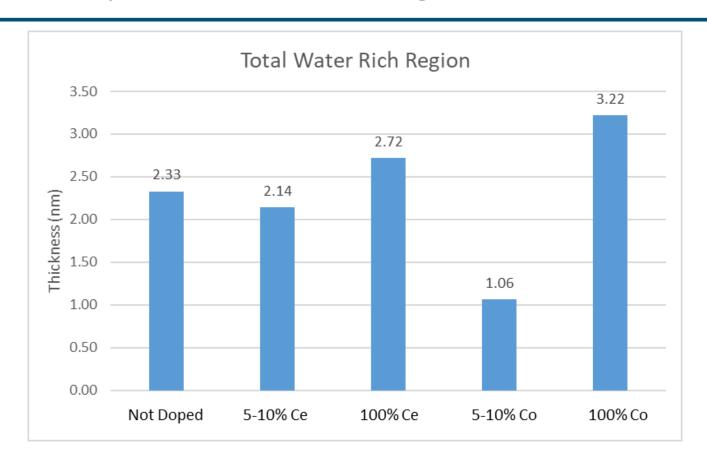




- Doping limits swelling
- Water uptake appears determined by if nafion is doped or not and is not a function of the amount of dopant
- Doping with Ce appears to decrease swelling as conc.
 Increases
- Ce appears to increase overall water content at high dopant levels and decrease overall water concentration at low dopant levels
- Doping with Co appears to slightly decrease overall water content under all conditions as a function of the amount of dopant



Effect of Dopant on Interface Region

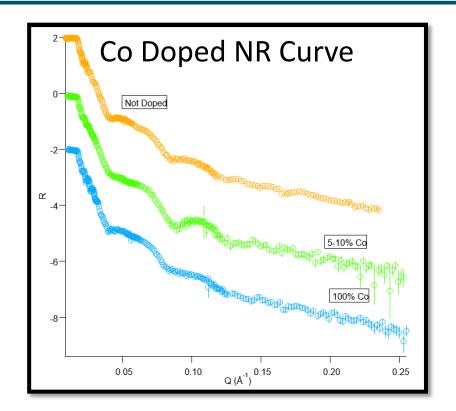


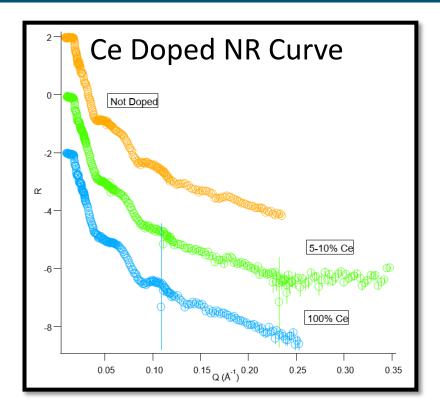
 Water-rich interface region increases at high dopant levels and decreases at low dopant levels



Effect of Co and Ce Exchange on Structure of Hydrated Nafion

Pt Substrate





No obvious Bragg peaks on Pt substrate

- No obvious layering structure
- In-depth modeling needed to determine structural differences
- Preliminary modeling suggests dense Nafion near substrate (consistent)



Summary / Futures

Objective:

♥ Use model systems to understand Nafion interactions/structure with Electrocatalysts (Pt/C)

Technical Accomplishments:

- ♦ Model system substrates of Si, Pt/Si and C/Pt
- Observe structural changes depending upon hydrophobicity of Pt surface (oxidized or metallic Pt)
- Measurements of membrane swelling with H₂O and D₂O
- Unit Different ionomer equivalent weights show different swelling
- ♦ Measured thin film ionomer structural changes in ionomer/water structure with cations
- Cations drastically change Nafion interface structure
 - (Cobalt (leaches out of PtCo/C (alloy) catalysts)
 - > (Cerium used for enhanced membrane chemical stability as a radical scavenger)

Future Work:

- ♦ Ionomer variations: Nafion, 3M825, 3M620 (equiv. wts)
- ♦ Additional variables and questions:
 - a) Carbon: variations of surface functionalities by partial oxidation
 - b) Surface oxidation of Pt by electrochemical potential variation
 - c) Ce and Co concentrations
 - d) Where is the Dopant in the film?



Supplemental Material



Structure Comparison and Chi Square Values

Samı	Sample 4			Sample 9				Sample 12				Sample 13				
Layers in r Dry Chi Sq H2O	Chi S D2O Chi Sqr	Layers in r Dry Ch	i Sq H2O Chi S	D2O Chi Sqr	Layers in r D	ry Chi Sq I	H2O Chi S	D2O Chi Sqr	Layers in r D	ry Chi Sq I	H2O Chi S	D2O Chi Sqr	Layers in r	Dry Chi Sq I	120 Chi S	D2O Chi Sqr
1 8.04467 19.	.4282 24.3042	1 7.35	993 34.4084	21.2414	1	15.2673	34.1862	12.6037	1	6.09846	43.7968	6.05808	1	8.15635	11.3123	10.0111
2 2.76741 6.	.4345 18.8118	2 3.6	101 4.07062	19.186	2	5.68895	12.8675	3.95165	2	2.35424	7.28234	4.58479	2	4.03816	26.8603	26.231
3 1.73995 6.0	09444 11.2484	3 3.2	127 6.81987	23.6886	3	3.5612	9.21055	9.05647	3	2.59696	4.37151	4.69145	3	1.53957	8.50793	9.95548
4 1.20335 3.	.4367 28.6708	4 1.28	118 2.97097	41.3139	4	1.9766	7.61511	7.72644	4	1.61799	2.66648	3.55537	4	1.70491	3.57004	7.54793
5 2.20476 1.	.7907 2.42745	5	2.72192	26.6642	5	2.72775	2.91715	4.1263 D2O Matc	5	1.73386	2.49636	3.5841	5	1.1751	2.0749	2.03435
6 2.4587 2.8	88709 2.15751 6Layer H2	6	2.08561	6.1 H2O	6	4.92927	4.55861	2.04861	6	0.83004	1.7279	4.2918 thin top la	6			
7		7			7		4.07219		7				7			
Di	Dry			Dry			Dry			Dry						
Layer Thickness SL	LD %H2O content	Layer Thickn	ess SLD	%H2O content	Layer Th	hickness	SLD	%H2O content	Layer Ti	hickness	SLD S	%H2O content	Layer	Thickness	SLD	%H2O content
1 59.339 3.	. <mark>6923</mark> 11%	1 68.	783 3.4245	17%	1	60.412	3.7098	10%	1	51.583	3.8175	8%	1	17.015	3.5391	15%
2 118.87 3.	.8605 7%	2 160	.69 3.6455	12%	2	211.59	3.9796	4%	2	118.56	3.9905	4%	2	38.863	3.6794	11%
3 27.145 3.	.5611 14%	3 26.	L64 3.1564	24%	3	44.099	3.2046	22%	3	18.124	3.8957	6%	3	128.92	3.9274	5%
4 <mark>10.051.</mark>	<mark>.8196</mark> 55%	4 10.	353 1.7331	57%	4	11.585	1.395	66%	4	23.167	3.6618	12%	4	33.366	3.7739	9%
5		5			5				5	9.812	1.7204	58%	5	10.048	1.9625	52%
6		6			6				6				6			
7		7			7				7				7			
Total thickness =	21.5 nm	Total thickness	= 26.6	nm	Total thick	ness =	32.8	nm	Total thick	kness =	22.1	nm	Total thic	kness =	22.8	nm
Average % Water = 11%		Average % Water = 16%		Average % Water = 10%			Average % Water = 8%			Average % Water = 10%						
H2O		H2O			H2O			H2O			H2O					
Layer Thickness SL	LD %H2O content	Layer Thickn	ess SLD	%H2O content	Layer Th	hickness	SLD	%H2O content	Layer Ti	hickness	SLD S	%H2O content	Layer	Thickness	SLD	%H2O content
1 252.01 2.	.6862 35%	1 32.	574 2.1665	47%	1	193.49	3.0509	26%	1	39.83	2.353	43%	1	37.847	1.9173	53%
2 6.6336 -0.0	99%	2 48.	396 2.9503	29%	2	157.89	2.9389	29%	2	99.285	2.9982	27%	2	44.438	2.8307	31%
3 10.091 5.	.8055 -39%	3 120	.66 2.8011	32%	3	8.4236	1.0219	74%	3	91.737	3.0845	25%	3	154.19	3.0678	26%
4 8.3264 -0.0	05662 100%	4 75.	316 2.6299	36%	4	34.11	2.9347	29%	4	11.859	2.2944	44%	4	48.299	2.752	33%
5 12.496 3.	.0423 26%	5 15.	169 3.2762	21%	5	13.017	0.31422	91%	5	21.84	3.0755	26%	5	10.634	0.92838	77%
6 8.3244 0.3	34056 91%	6 27.	215 0.79703	80%	6				6	20.324	1.5	63%	6			
7		7			7				7				7			
Total thickness = 29.8 nm		Total thickness = 32.0 nm		Total thickness = 40.7 nm			Total thickness = 28.5 nm			Total thic	kness =	29.5	nm			
Average % Water =	37%	Average % Wate	r = 38%		Average %	Water =	30%		Average %	Water =	32%		Average %	Water =	33%	



Modeling of Ionomer Films

- Software: MOTOFIT.
- Create model consisting of multiple layers
- Each layer has three variables: thickness, roughness at the interface, and SLD (scattering length density)
- SLD contains information about chemical composition.
- Model calculates the reflectivity of a sample with that structure, calculates a chi square of the fit, and continues that iteration until a minimum in the chi squared is found.
- Best-fit reflectivity curve and the SLD profile that generates that curve.
- SLD profile is a function of depth into the sample.
- Use of multiple layers used to find further structure in the water distributions within the polymer layer.
 - Adjust the slds in other locations.
 - Surface roughness between these layers can be extremely high and yield a
 distribution that looks almost linear across the film, or the roughness may be more
 narrow in preference of more distinct regions.



Comments

- We repeated the measurements of the 3M polymers on Pt in dry conditions and confirmed the non-uniform polymer distribution in the film (less density at the air interface). That complicates things substantially for those 2 cases, especially trying to be quantitative about the water distribution after swelling.
- Mixed H_2O and D_2O in ratio for SLD variance to be = zero. Exposed to vapor, to look at polymer distribution with no net change from water. Showed same distribution as H_2O .
- Exacting water concentrations/gradient in the films
- The samples equilibrate for about an hour. Samples remain in controlled atmosphere during neutron reflectometry. The data are usually taken somewhere between 12 and 24 hours per sample. The modelling time varies, but ~ 2-3 hours per dataset

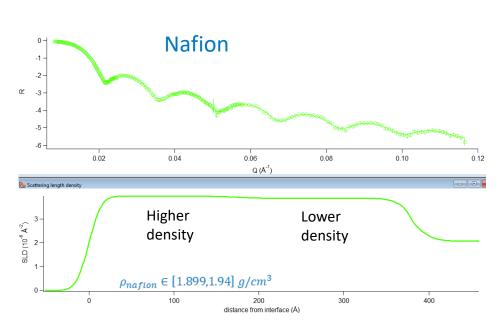


Ionomer Swelling and SLD for Nafion, 3M825, 3M620

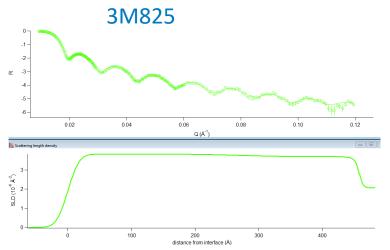
					% Volume
		Thickness	SLD	% Swelling	Fraction D2O
Nafion on Si (Dry)	Dry	366	3.89		
Nafion on Si (Wet)	Wet	434	4.74	19%	35%
Nafion on Pt (Dry)	Dry	407	4.19		
Nafion on Pt (Wet)	Wet	496	4.84	22%	31%
3M825 on Si (Dry)	Dry	440	3.79		
3M825 on Si (Wet)	Wet	542	4.84	23%	42%
3M825 on Pt (Dry)	Dry	464	3.98		
3M825 on Pt (Wet)	Wet	553	5.16	19%	51%
3M620 on Si (Dry)	Dry	318	3.3		
3M620 on Si (Wet)	Wet	620	5.11	95%	60%
3M620 on Pt (Dry)	Dry	353	3.44		
3M620 on Pt (Wet)	Wet	559	5.18	58%	61%

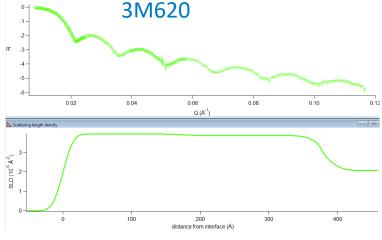


Dry Ionomer Films on Si Substrates



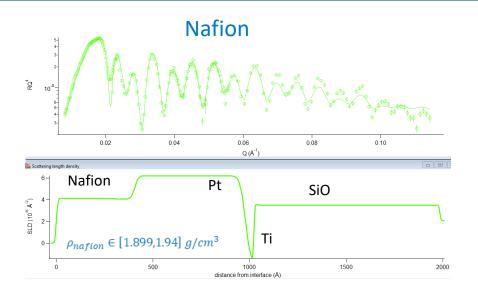
- All ionomers slightly decrease in density toward substrate
- Similar feature for Nafion on Pt

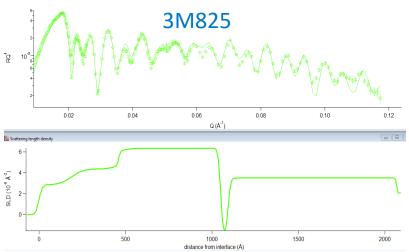




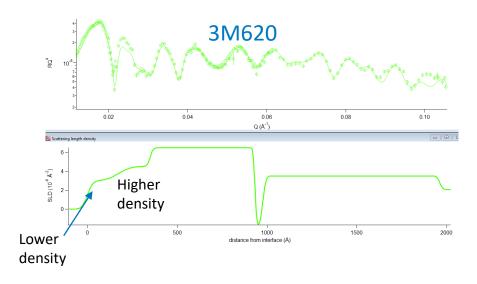


Dry Ionomer Films on Pt Substrates





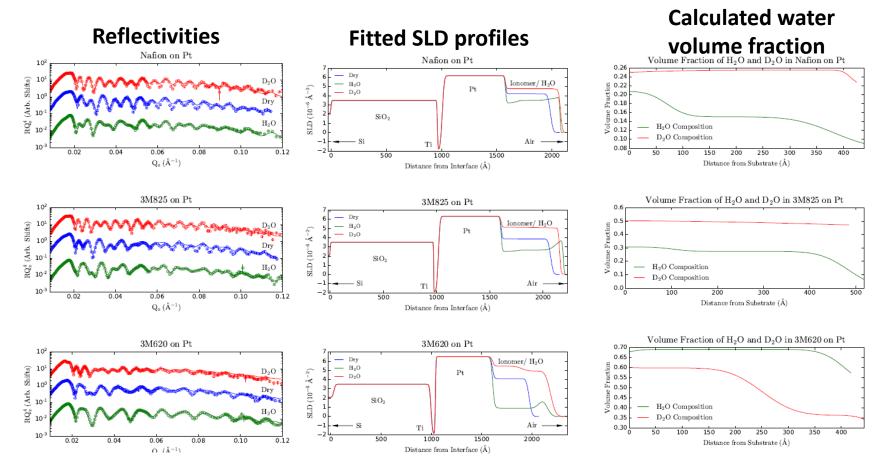
- Nafion decreases in density toward Pt substrate.
- 3M ionomers increase in density toward Pt substrate (repeated)





Combined H₂O and D₂O for zero SLD

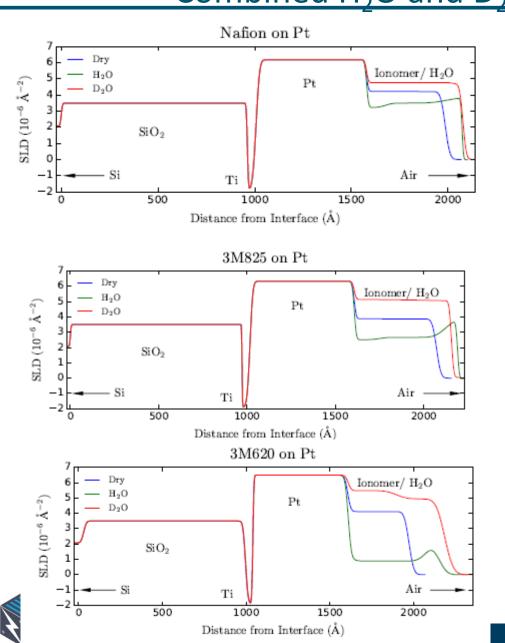
Nafion, 3M825, 3M620 Ionomers

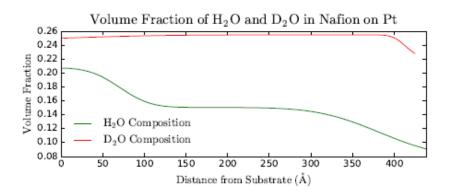


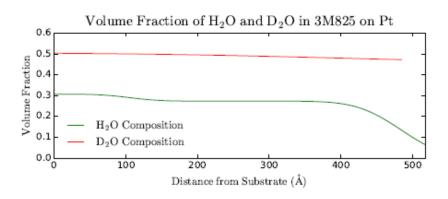
Fits show good agreement demonstrating water concentrations are higher near the surface of the Pt substrate

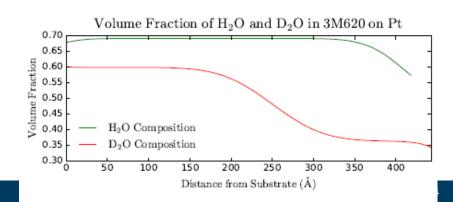


Fitted SLD profiles Combined H₂O and D₂O for zero SLD



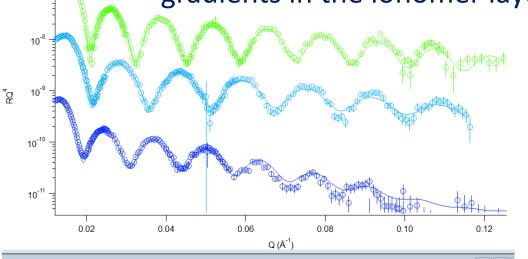




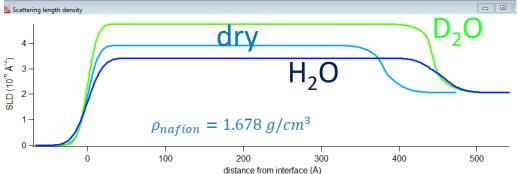


NR of Nafion on Si, Dry and Wet (H₂O and D₂O)

2 Layer Model. Does not account for concentration gradients in the ionomer layers. (2 Layers = Si, Nafion)



Good Fit



D₂O: 16.9% Swell

 $x_{D2O} = 33.7\%$

H₂O: 18.1% Swell

 $X_{H2O} = 11.1\%$

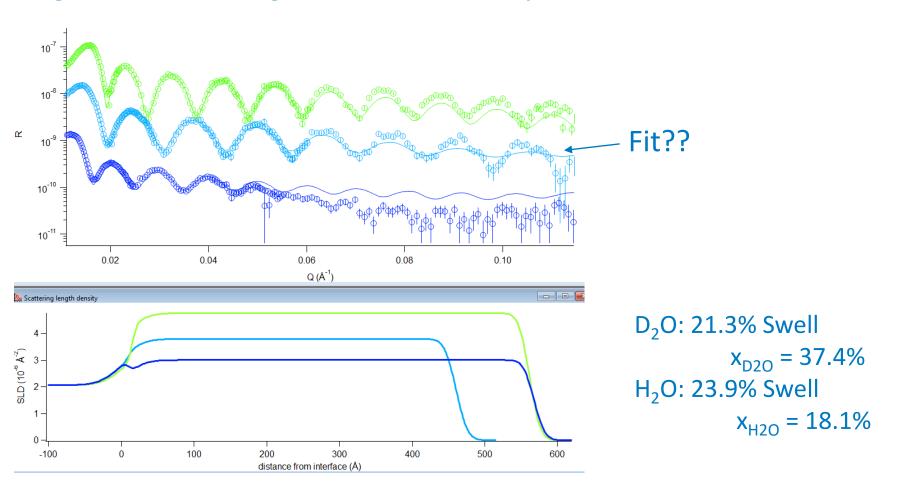
Note:

D₂O positive coherent scattering length H₂O negative coherent scattering length



3M825

High Q fits are not good. Need more layers.

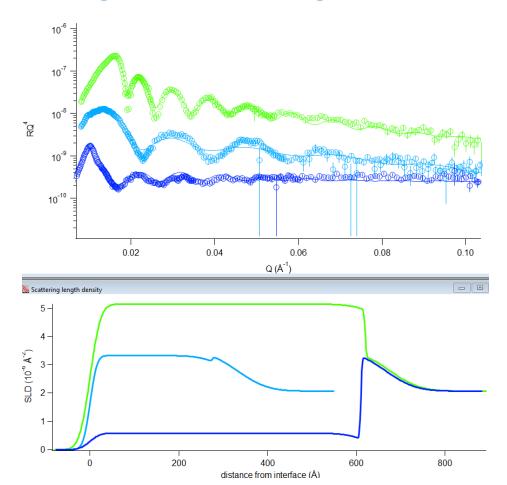


As side chain density increases, structure is more complicated



3M620

High Q fits are not good. Need more layers.

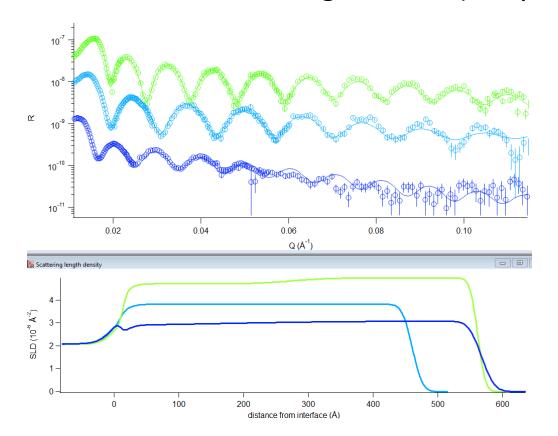


As side chain density increases, structure is more complicated



3M825/Si – 3 Layer Model

3 Layer Model. Add extra layer to ionomer to see concentration gradients. (3 Layers – Si, 2 layers of ionomer)

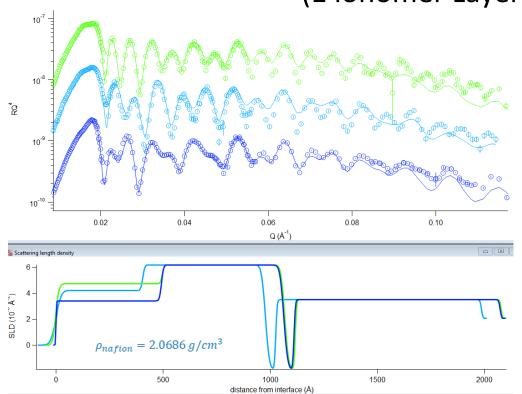


Much better fit with 3layer model (2 ionomer layers)

→ 3M ionomers have more complicated structure than does Nafion

Nafion/Pt/Ti/Si – 4 Layer Model





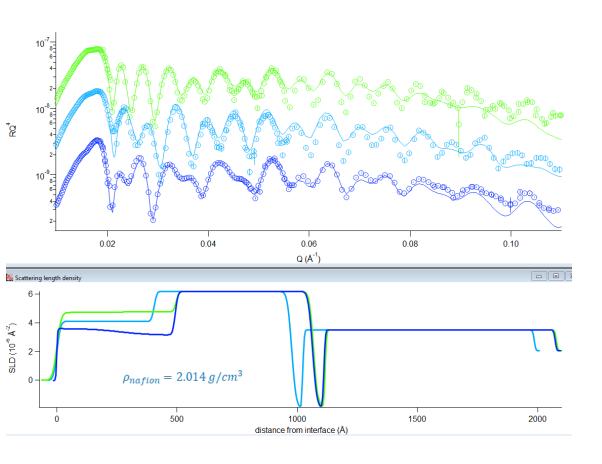
Model captures major features, but high Q loses structure. Needs more layers

$$D_2O$$
: 22.4% Swell $x_{D2O} = 24.0\%$ H_2O : 21.3% Swell $x_{H2O} = 20.0\%$

Nafion has simple structure on Si, but more complicated structure on Pt



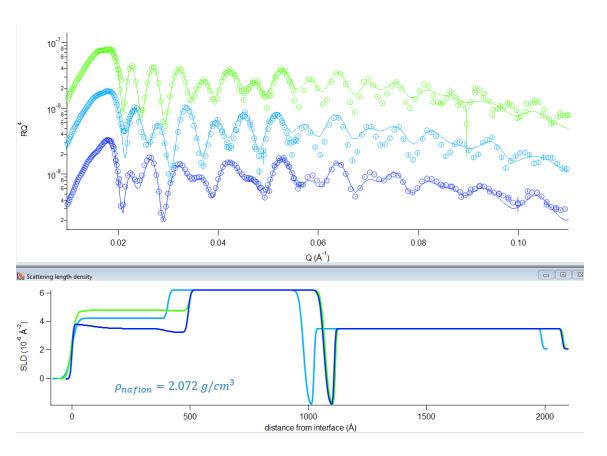
Nafion/Pt/Ti/Si – 5 Layer Model



2 ionomer layer model captures major features, but high Q loses structure. Still needs more layers



Nafion/Pt/Ti/Si – 6 Layer Model



3-ionomer layer model shows high Q structure now present in fit when water concentration increases near Pt surface.

Nafion requires 3 ionomer layers to adequately describe structure on Pt

